Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/774,607	NAKAI, SHINYA	
Examiner	Art Unit	
Tuan A. Tran	2618	

SEARCHED			
Class	Subclass	Date	Examiner
455	78-83	11/10/2006	TT
455	73,550.1		
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INTERFERENCE SEARCHED				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
DATE	EXMR			
11/10/2006	TT			
12/12/2006	тт			
12/12/2006	т			
	DATE 11/10/2006 12/12/2006			

Search Notes (continued)

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Application/Control No.	Applicant(s)/Patent under Reexamination		
10/774,607	NAKAI, SHINYA		
Examiner	Art Unit		
Tuan A. Tran	2618		

SEARCHED					
Class	Subclass	Date		Examiner	
257	664,347	11/10/2006		тт	
343	700MS				
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343	701-702				· · · · ·
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST (USPAT, USPGPUB, USOCR, FPRS, JPO, EPO, DERWENT)	11/10/2006	т	
EAST (USPAT, USPGPUB, USOCR, FPRS, JPO, EPO, DERWENT)	12/12/2006	тт	